

MOTOROLA SEMICONDUCTOR TECHNICAL DATA

Advance Information

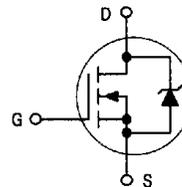
TMOS E-FET™

Power Field Effect Transistor

N-Channel Enhancement-Mode Silicon Gate

This advanced TMOS E-FET is designed to withstand high energy in the avalanche and commutation modes. The new energy efficient design also offers a drain-to-source diode with a fast recovery time. Designed for high voltage, high speed switching applications in power supplies, converters and PWM motor controls, these devices are particularly well suited for bridge circuits where diode speed and commutating safe operating areas are critical and offer additional safety margin against unexpected voltage transients.

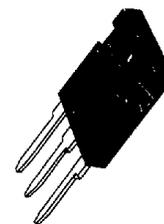
- Avalanche Energy Specified
- Source-to-Drain Recovery Time Comparable to a Discrete Fast Recovery Diode
- Diode is Characterized for Use in Bridge Circuits
- I_{DSS} and $V_{DS(on)}$ Specified at Elevated Temperature



MTW8N50E

Motorola Preferred Device

TMOS POWER FET
8.0 AMPERES
 $R_{DS(on)} = 0.80 \text{ OHM}$
500 VOLTS



CASE 340F-03
TO-247AE

MAXIMUM RATINGS ($T_J = 25^\circ\text{C}$ unless otherwise noted)

| Rating | Symbol | Value | Unit |
|--|-----------------|------------|---------------------|
| Drain-Source Voltage | V_{DSS} | 500 | Vdc |
| Drain-Gate Voltage ($R_{GS} = 1.0 \text{ M}\Omega$) | V_{DGR} | 500 | Vdc |
| Gate-Source Voltage — Continuous | V_{GS} | ± 20 | Vdc |
| Drain Current — Continuous @ $T_C = 25^\circ\text{C}$ | I_D | 8.0 | Adc |
| — Continuous @ $T_C = 100^\circ\text{C}$ | I_D | 5.0 | |
| — Single Pulse ($t_p \leq 10 \mu\text{s}$) | I_{DM} | 32 | Apk |
| Total Power Dissipation @ $T_C = 25^\circ\text{C}$ | P_D | 150 | Watts |
| Derate above 25°C | | 1.0 | W/ $^\circ\text{C}$ |
| Operating and Storage Temperature Range | T_J, T_{stg} | -55 to 150 | $^\circ\text{C}$ |
| Single Pulse Drain-to-Source Avalanche Energy — Starting $T_J = 25^\circ\text{C}$ ($V_{DD} = 50 \text{ Vdc}$, $V_{GS} = 10 \text{ Vpk}$, $I_L = 8.0 \text{ Apk}$, $L = 10.4 \text{ mH}$, $R_G = 25 \Omega$) | EAS | 430 | mJ |
| Thermal Resistance — Junction to Case | $R_{\theta JC}$ | 1.0 | $^\circ\text{C/W}$ |
| — Junction to Ambient | $R_{\theta JA}$ | 40 | |
| Maximum Lead Temperature for Soldering Purposes, 1/8" from case for 5 seconds | T_L | 260 | $^\circ\text{C}$ |

This document contains information on a new product. Specifications and information are subject to change without notice.

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Preferred devices are Motorola recommended choices for future use and best overall value.

ELECTRICAL CHARACTERISTICS ($T_C = 25^\circ\text{C}$ unless otherwise noted)

| Characteristic | Symbol | Min | Typ | Max | Unit |
|----------------|--------|-----|-----|-----|------|
|----------------|--------|-----|-----|-----|------|

OFF CHARACTERISTICS

| | | | | | |
|---|------------|----------|----------|-------------|-----------------|
| Drain-Source Breakdown Voltage ($V_{GS} = 0\text{ V}$, $I_D = 250\ \mu\text{Adc}$) Temperature Coefficient (Positive) | BV_{DSS} | 500 — | — 500 | — — | Vdc mV/°C |
| Zero Gate Voltage Drain Current ($V_{DS} = 500\text{ Vdc}$, $V_{GS} = 0$) ($V_{DS} = 500\text{ Vdc}$, $V_{GS} = 0$, $T_J = 125^\circ\text{C}$) | I_{DSS} | — — | — — | 250 1000 | μAdc |
| Gate-Body Leakage Current ($V_{GS} = \pm 20\text{ Vdc}$, $V_{DS} = 0$) | I_{GSS} | — | — | 100 | nAdc |

ON CHARACTERISTICS*

| | | | | | |
|--|--------------|----------|----------|------------|--------------|
| Gate Threshold Voltage ($V_{DS} = V_{GS}$, $I_D = 250\ \mu\text{Adc}$) Temperature Coefficient (Negative) | $V_{GS(th)}$ | 2.0 — | — 5.0 | 4.0 — | Vdc mV/°C |
| Static Drain-Source On-Resistance ($V_{GS} = 10\text{ Vdc}$, $I_D = 4.0\text{ Adc}$) | $R_{DS(on)}$ | — | — | 0.8 | Ohm |
| Drain-Source On-Voltage ($V_{GS} = 10\text{ Vdc}$) ($I_D = 8.0\text{ Adc}$) ($I_D = 4.0\text{ Adc}$, $T_J = 125^\circ\text{C}$) | $V_{DS(on)}$ | — — | — — | 7.6 6.4 | Vpk |
| Forward Transconductance ($V_{DS} = 50\text{ Vdc}$, $I_D = 4.0\text{ Adc}$) | g_{FS} | 4.0 | — | — | mhos |

DYNAMIC CHARACTERISTICS

| | | | | | | |
|------------------------------|--|-----------|---|------|------|----|
| Input Capacitance | $(V_{DS} = 25\text{ Vdc}$, $V_{GS} = 0$, $f = 1.0\text{ MHz}$) | C_{iss} | — | 1200 | 1800 | pF |
| Output Capacitance | | C_{oss} | — | 176 | 264 | |
| Reverse Transfer Capacitance | | C_{rss} | — | 72 | 108 | |

SWITCHING CHARACTERISTICS*†

| | | | | | | |
|---------------------|--|--------------|---|----|-----|----|
| Turn-On Delay Time | $(V_{DD} = 250\text{ Vdc}$, $I_D = 8.0\text{ Adc}$, $V_{GS} = 10\text{ Vdc}$, $R_g = 9.1\ \Omega$) | $t_{d(on)}$ | — | 25 | 50 | ns |
| Rise Time | | t_r | — | 36 | 72 | |
| Turn-Off Delay Time | | $t_{d(off)}$ | — | 75 | 150 | |
| Fall Time | | t_f | — | 30 | 60 | |
| Gate Charge | $(V_{DS} = 400\text{ Vdc}$, $I_D = 8.0\text{ Adc}$, $V_{GS} = 10\text{ Vdc}$) | Q_T | — | 92 | 125 | nC |
| | | Q_1 | — | 12 | — | |
| | | Q_2 | — | 45 | — | |
| | | Q_3 | — | 35 | — | |

SOURCE-DRAIN DIODE CHARACTERISTICS*

| | | | | | | |
|--|--|----------|------------|----------|---------------|----|
| Forward On-Voltage ($I_S = 8.0\text{ Adc}$, $V_{GS} = 0$) ($I_S = 8.0\text{ Adc}$, $V_{GS} = 0$, $T_J = 125^\circ\text{C}$) | V_{SD} | — — | 1.1 1.0 | 2.0 — | Vdc | |
| Reverse Recovery Time | $(I_S = 8.0\text{ Adc}$, $V_{GS} = 0$, $di_S/dt = 100\text{ A}/\mu\text{s}$) | t_{rr} | — | 420 | — | ns |
| | | t_a | — | 280 | — | |
| | | t_b | — | 140 | — | |
| Reverse Recovery Stored Charge | Q_{RR} | — | 4.4 | — | μC | |

INTERNAL PACKAGE INDUCTANCE

| | | | | | |
|--|-------|--------|----------|--------|----|
| Internal Drain Inductance (Measured from the contact screw on tab to center of die) (Measured from the drain lead 0.25" from package to center of die) | L_D | — — | — 5.0 | — — | nH |
| Internal Source Inductance (Measured from the source lead 0.25" from package to source bond pad) | L_S | — | 13 | — | nH |

*Pulse Test Pulse Width $\leq 300\ \mu\text{s}$, Duty Cycle $\leq 2\%$

† Switching characteristics are independent of operating junction temperature